

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10562226	NAKAMURA, TOSHIO
Examiner	Art Unit	
Strieb, Michael A	2809	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
Met with Benny Tieu	08/30/2007	MAS
Met with Sam Walk	8/30/2007	MAS
EAST text search	8/31/2007	MAS
Consulted with Primary Examiner William Perkey	6/5/2008	MAS

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner